



Fabrication optimization to enhance micro-resonator yield



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FABRICATION OPTIMIZATION TO ENHANCE MICRO-RESONATOR YIELD

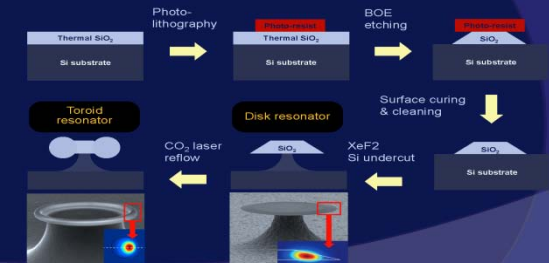
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Applications that will benefit

- ◆ Cavity QED
 - Q and V are key figures of merit.
 - Q is very sensitive to side wall roughness and structure symmetry
- ◆ Cascaded higher-order optical resonator
 - Yield of n^{th} order resonator \leq (Yield of single resonator) n
- ◆ Large and complex structures based on micro disk and toroid

General Fabrication procedure



Approach - Increasing fabrication yield

- ◆ Optimization of fabrication process
 - Increasing surface uniformity by sacrificing dimension definition
 - Non-contact UV exposure by stepper
 - Macro-scale structure uniformity and fabrication yield
 - PEB (post exposure bake) and hard-bake (reflow)
 - Surface roughness
 - BOE (buffered oxide etcher) applying time control
 - Surface roughness and discontinuity on side wall

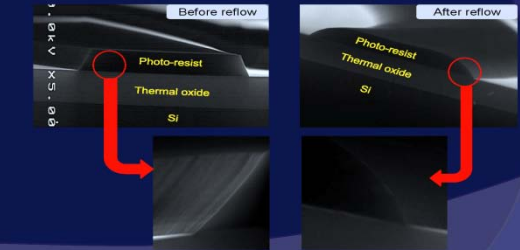
Non-contact exposure and PEB

- ◆ Non-contact UV exposure by KNI stepper
 - GCA-6300 DSW stepper
 - 365 nm exposure wavelength
 - 0.5 μm resolution, 10mm x 10mm field size
 - Non-contact between mask and wafer
 - increasing uniformity and quality → increasing fabrication yield
- ◆ Post exposure bake (PEB)
 - PEB (PAC diffusion) & developing



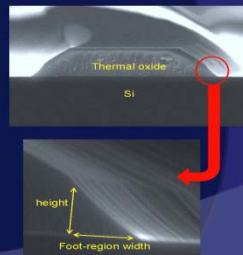
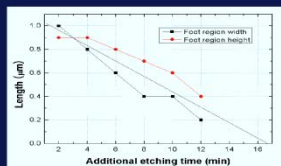
Decreasing side wall roughness

Photo-resist reflow

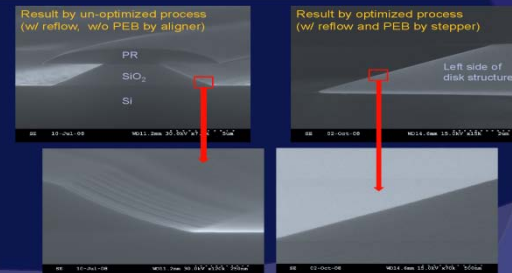


Elimination of discontinuity on side wall

- ◆ Foot-region on side wall
 - Increasing additional etching time
 - decreasing foot-region size



Result of optimized fabrication



Q-Measurement Results

- ◆ Q distribution of disks groups fabricated by different conditions
 - More than 15 disks were tested to estimate Q distribution for each fabrication condition.

Exposure method	Bake	Average Q
Aligner (contact)	Reflow	0.8 M
Aligner (contact)	Reflow & PEB	3 M
Stepper (non-contact)	Reflow & PEB	17 M

